

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/633,105	HAN ET AL.	
Examiner	Art Unit	_
Mark Blouin	2627	

SEARCHED					
Subclass	Date	Examiner			

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
360	126	6/2/16	VV)		
29	603	4/7/06	v~3		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
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Text Scardel 36929 See EAST 1/2 kmg	6/7/06	vs			